Application/Control No. Applicant(s)/Patent Under Reexamination 10/045,348 SHIN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Mark A. Mais 2616 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-6,400,730 06-2002 Latif et al. 370/466 Α * US-6,971,044 11-2005 Geng et al. 714/11 В С US-2002/0049825 04-2002 Jewett et al. 709/215 US-D US-Ε US-F US-G US-Н US-US-J

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